



Manufacturers of flat, large area, high technology products such as photovoltaic, LCD & plasma panels, are faced with a series of increasingly challenging tasks when performing detailed, high magnification inspection of their products. Often, sensitive structures and features such as micro circuits, coatings, LCD pixels, inclusions and other anomalies, present a number of unique inspection challenges, requiring a balance of well optimized illumination, flexible magnification, in addition to traditional microscopy-based optical filtering techniques in order to capture useful images with high contrast.

Large Area Inspection with Differential Interference Contrast (DIC)

As part of the established lineup of automated SectorInspector systems, Opto now launches the **SectorInspector Manual**. This new version offers a perfect balance of price and performance in an all-manual configuration uniquely fitted with powerful Differential Interference Contrast

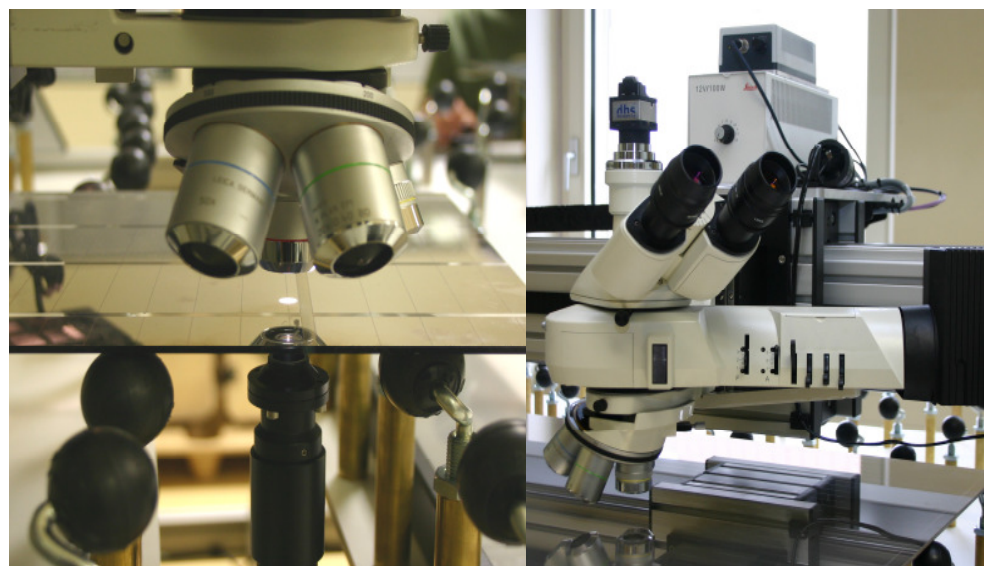
(DIC) function. This unique function enables perfect, high-contrast, high resolution imagery to be captured of even the most challenging microscopic features. Completing the system is a dedicated image capture software suite with image databasing, providing the perfect tool for quality assurance in documenting microscopic features or anomalies.

Intuitive operation

Manual positioning of the microscope and the simplicity of a ball castor array enables highly intuitive operation of the SectorInspector Manual – no training concerning positioning or control software is necessary. With this system, the operator can focus entirely on performing perfect microscopy on large area samples.

Optical Excellence & Perfect Illumination

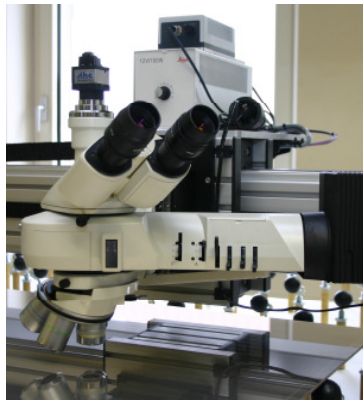
SectorInspector is designed to offer maximum imaging quality and flexibility. In addition to integrated bright field illumination (100W) the system incorporates a unique synchronized transmitted LED Koehler illuminator which is fully adjustable. The combination of both illumination techniques enables optimum imaging conditions for a wide variety of features. Adjustable differential interference contrast offers an additional mode to visualize traditionally challenging, transparent structures at a very high contrast.





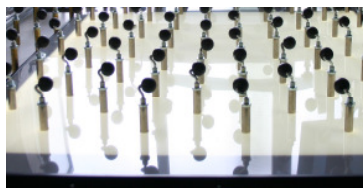
Intuitive positioning

- Standard configuration accommodates samples with dimensions up to 1300mm x 1100mm
Custom sizing available on request
- High accuracy manual gear drive enables precision positioning of microscope in horizontal transversal direction.
- Automatic underside synchronized positioning of transmitted light module to microscope
- Ball Castor Array enables samples to be accurately and effortlessly positioned under the microscope system



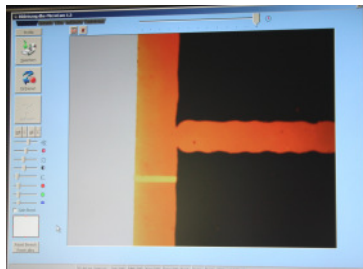
Microscope (Differential Interference Contrast)

- Brightfield light microscope with trinocular tube, 1.3 Megapixel camera and 10x eye-pieces
- Objective turret with objectives 5x/10x/20x/50x
- Integrated focusing block (coarse & fine) with 50mm travel range
- Onboard DIC-contrast equipment for all objectives
- Brightfield / Darkfield modes
- Daylight filter
- Adjustable LED transmitted light mode (Koehler)



Lightpanel for visual inspection

- Integrated light panel enables preliminary visual inspection without microscopy
- Adjustable active light field 1300mm x 1000mm integrated into Ball Castor Array



User interface

- Acquisition and documentation the image data with the image database
- Calibrated measurement suite enables very high accuracy measurements to be taken from identified features & structures.
- Fully integrated databasing enables mass image storage and archiving with integrated reporting

As the designer and manufacturer of the SectorInspector Manual, we are able to customise your system to whatever configuration and featureset you may require!